The Electron Spectro Microscopy beamline at NSLS II: a wide photon energy range, micro-focusing beamline for photoelectron spectro-microscopies.

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ESM is a new high-resolution, wide-energy range, micro-focused beamline working in the vacuum ultraviolet and soft x-ray photon energy range at NSLS II. It provides highly polarized, monochromatic radiation to two photoelectron microscopes: a scanning instrument dedicated to angle resolved photoemission spectroscopy (μ - ARPES) and a full-field x-ray photoelectron emission microscope (XPEEM). In the past year the beamline has been commissioned and operation has started in February 2018. Commissioning results pertaining to both the beamline and the end-stations will be presented.